

Notice of References Cited	Application/Control No. 09/740,889	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Tan Dean Nguyen	Art Unit 3629	Page 1 of 1

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NON-PATENT DOCUMENTS

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	V	Baxter, J.J. "Resource ...Multicomputers", University of Illinois at Urbana-Champaign, 1992.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.